

Search Notes

Application/Control No.

10/617,172

Examiner

Tianjie Chen

Applicant(s)/Patent under
Reexamination

KIM ET AL.

Art Unit

2627

SEARCHED

Class	Subclass	Date	Examiner
Updated		5/4/2007	TJ

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR